

Search Notes

Application/Control No.

10/646,823

Examiner

Hai L. Nguyen

Applicant(s)/Patent under
Reexamination

ISHIMI, KOICHI

Art Unit

2816

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|---|-----------|----------|
| 327 | 116,119, 146,147, 149,151, 158 | 4/17/2005 | HLN |
| | 153-156 | | |
| | 160-163 | | |
| | 291-294 | | |
| 331 | 25,34,53 | | |
| - | DIG.2 | | |
| 375 | 373-376 | | |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
|--------|----------|-----------|----------|
| Search | Above | 4/17/2005 | HLN |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|-------------------|-----------|------|
| Shepardize Search | 4/17/2005 | HLN |
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